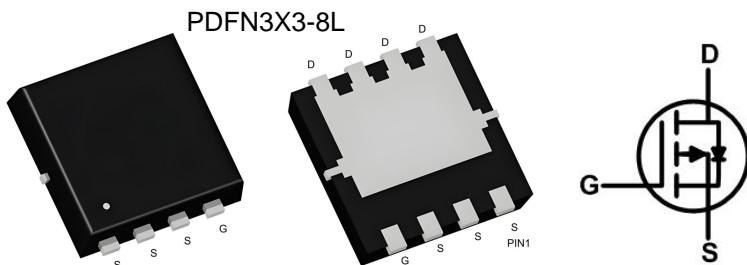


P-Channel 20V(D-S) MOSFET

Product summary			Features
V_{DS}	-20	V	<ul style="list-style-type: none"> Advanced Trench technology Low Gate Charge
$R_{DS(ON)}$ (at $V_{GS}=-4.5V$) Typ.	6	$m\Omega$	Applications
$R_{DS(ON)}$ (at $V_{GS}=-2.5V$) Typ.	8	$m\Omega$	<ul style="list-style-type: none"> Load switching PWM Applications Power Management
$I_D(T_c=25^\circ C)$	-50	A	

Pin Configuration



Packing Information

Device	Package	Reel Size	Quantity(Min. Package)
ECAL50P02B	PDFN3X3-8L	13 "	5000pcs

Absolute Maximum Ratings (at $T_A=25^\circ C$ Unless Otherwise Noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	-20	V
V_{GS}	Gate-Source Voltage	± 12	V
I_D	Continuous Drain Current	$T_c=25^\circ C$	A
		$T_c=100^\circ C$	A
I_{DM}	Pulse Drain Current Tested ^A	-210	A
E_{AS}	Single Pulse Avalanche Energy ^B	43	mJ
P_D	Power Dissipation $T_c=25^\circ C$	42	W
T_J, T_{STG}	Junction and Storage Temperature Range	-55 to +150	°C

Thermal Characteristics

Symbol	Parameter	Typical	Units
R_{eJC}	Thermal Resistance-Junction to case max	3	°C/W

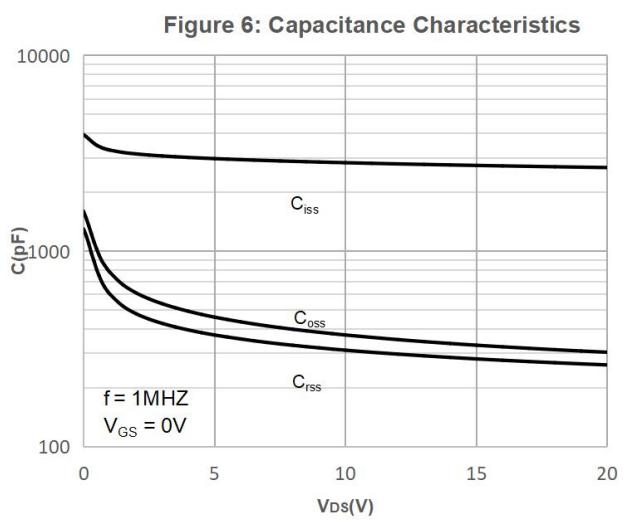
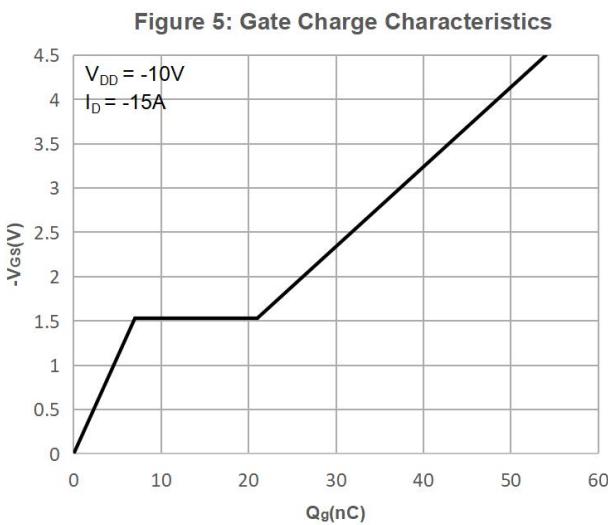
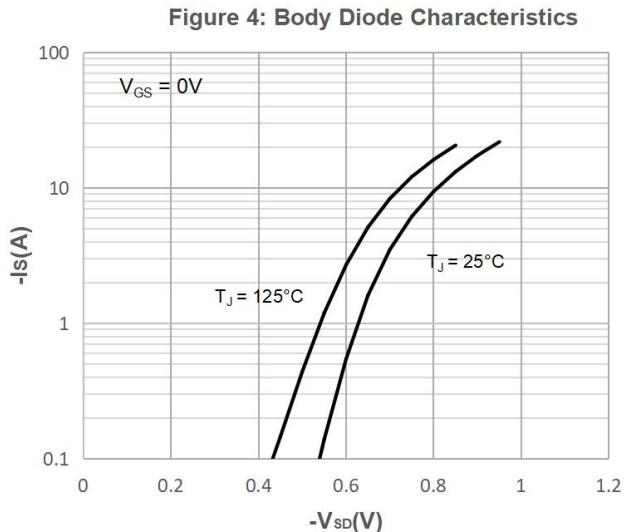
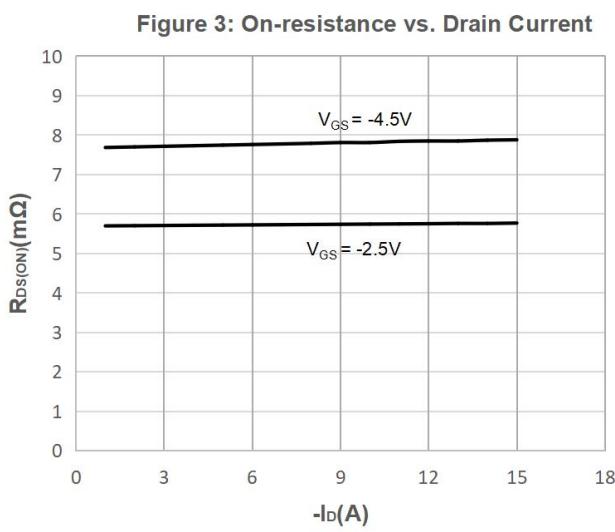
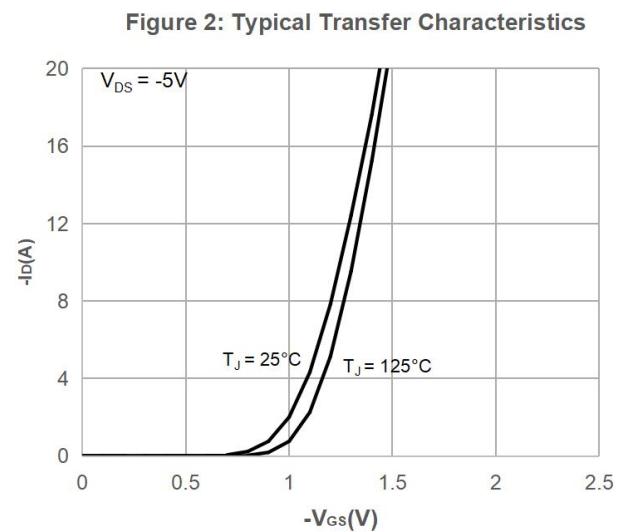
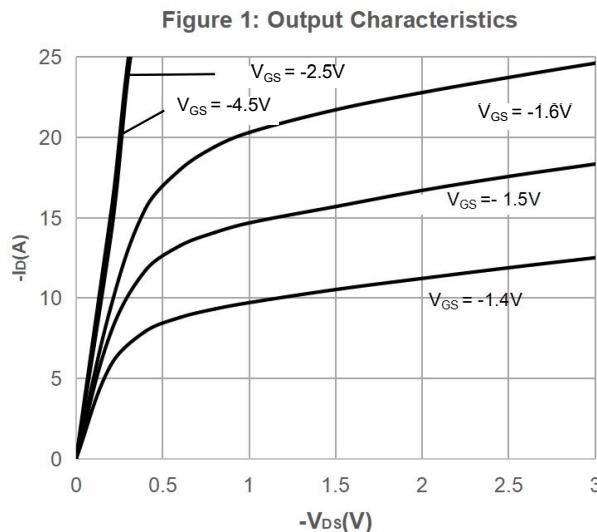
Electrical Characteristics (at $T_J = 25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
Static Parameters						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=-250\mu\text{A}$	-20	--	--	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}}=-20\text{V}, V_{\text{GS}}=0\text{V}$	--	--	-1	μA
I_{GSS}	Gate-Body Leakage Current	$V_{\text{DS}}=0\text{V}, V_{\text{GS}}=\pm 12\text{V}$	--	--	± 100	nA
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=-250\mu\text{A}$	-0.4	-0.65	-1.0	V
$R_{\text{DS}(\text{ON})}$	Drain-Source On-State Resistance ^C	$V_{\text{GS}}=-4.5\text{V}, I_{\text{D}}=-15\text{A}$	--	6	8	$\text{m}\Omega$
		$V_{\text{GS}}=-2.5\text{V}, I_{\text{D}}=-10\text{A}$	--	8	10	$\text{m}\Omega$
V_{SD}	Diode Forward Voltage	$I_{\text{S}}=-10\text{A}, V_{\text{GS}}=0\text{V}$	--	--	-1.2	V
Dynamic Parameters ^D						
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=-10\text{V}$ $f=1\text{MHz}$	--	2830	--	pF
C_{oss}	Output Capacitance		--	375	--	pF
C_{rss}	Reverse Transfer Capacitance		--	310	--	pF
Q_g	Total Gate Charge	$V_{\text{DS}}=-10\text{V}, I_{\text{D}}=-15\text{A}$ $V_{\text{GS}}=0 \text{ to } -4.5\text{V}$	--	54	--	nC
Q_{gs}	Gate-Source Charge		--	7	--	nC
Q_{gd}	Gate-Drain Charge		--	14	--	nC
$t_{\text{D}(\text{on})}$	Turn-on Delay Time	$V_{\text{DD}}=-10\text{V}$ $I_{\text{D}}=-13\text{A}, V_{\text{GS}}=-10\text{V},$ $R_{\text{GEN}}=3\Omega$	--	13	--	ns
t_r	Turn-on Rise Time		--	105	--	ns
$t_{\text{D}(\text{off})}$	Turn-off Delay Time		--	145	--	ns
t_f	Turn-off Fall Time		--	150	--	ns
t_{rr}	Reverse recovery time	$I_{\text{F}}=-15\text{A},$ $di/dt=100 \text{ A/uS}$	--	26	--	ns
Q_{rr}	Reverse recovery charge		--	15	--	nC

Note:

- A. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.
- B. The EAS data shows Max. rating . The test condition is $V_{\text{DD}}=-10\text{V}, V_{\text{G}}=-10\text{V}, L=0.5\text{mH}, I_{\text{AS}}=-13\text{A}, R_{\text{g}}=25\Omega, T_J=25^\circ\text{C}$.
- C. Pulse Test: Pulse Width $\leq 300\text{us}$, Duty cycle $\leq 2\%$.
- D. Guaranteed by design, not subject to production testing.

Typical Characteristics



Typical Characteristics

Figure 7: Normalized Breakdown voltage vs. Junction Temperature

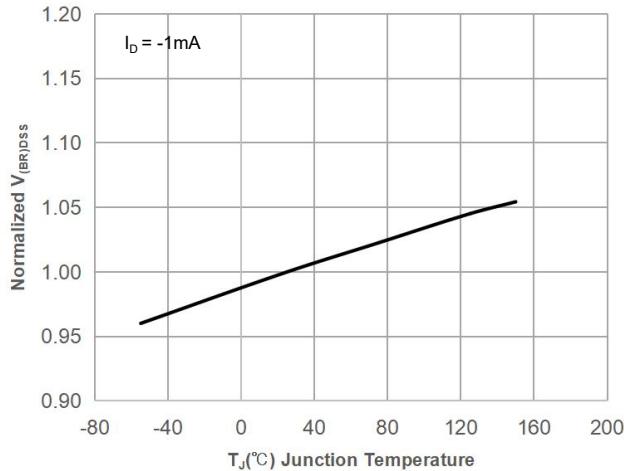


Figure 8: Normalized on Resistance vs. Junction Temperature

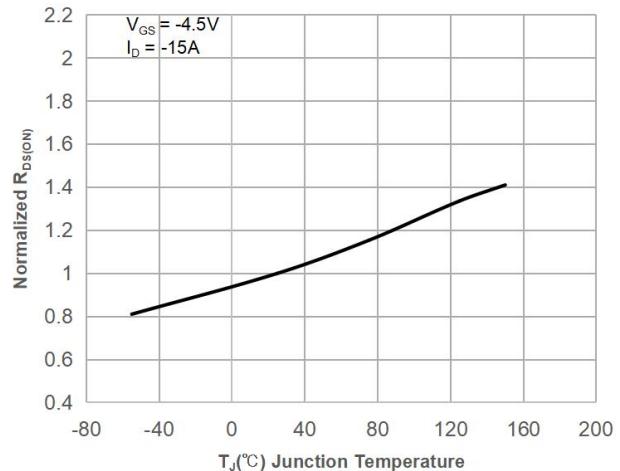


Figure 9: Maximum Safe Operating Area

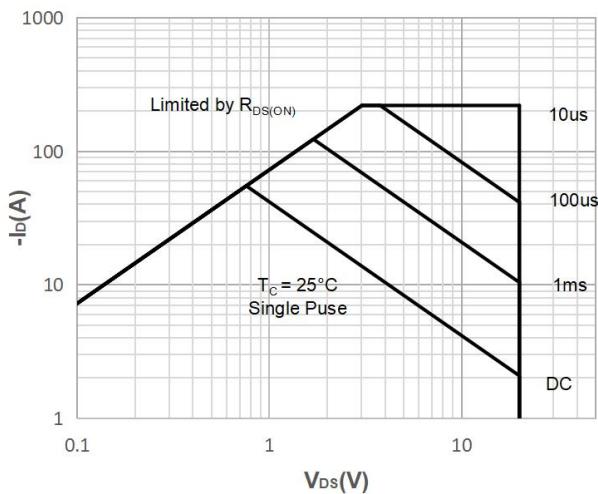


Figure 10: Maximum Continuous Drain Current vs. Case Temperature

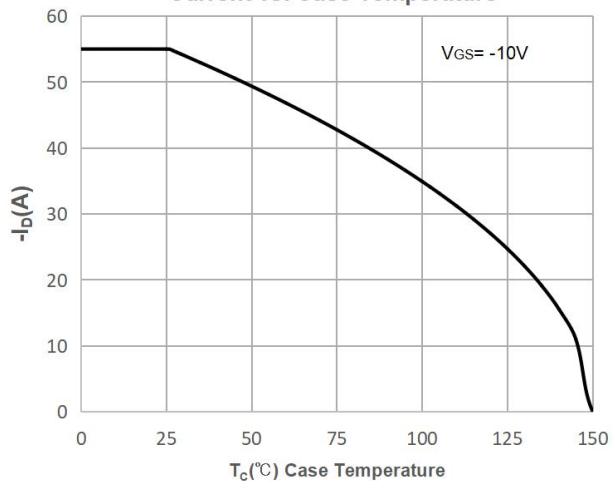


Figure 11: Normalized Maximum Transient Thermal Impedance

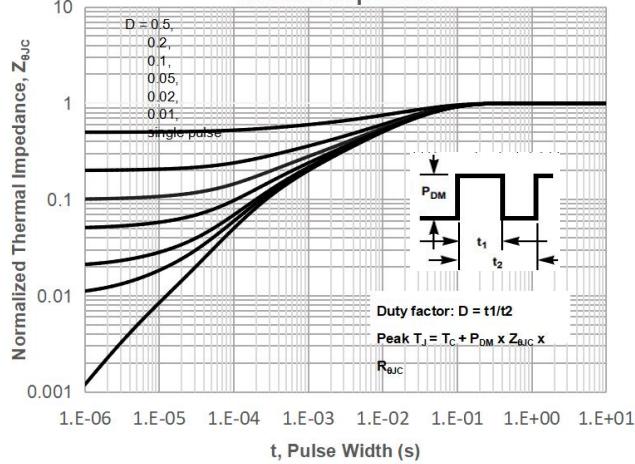
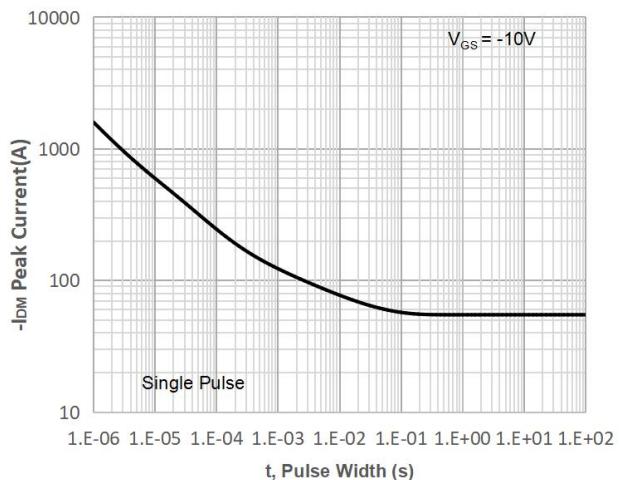


Figure 12: Peak Current Capacity



Test Circuit

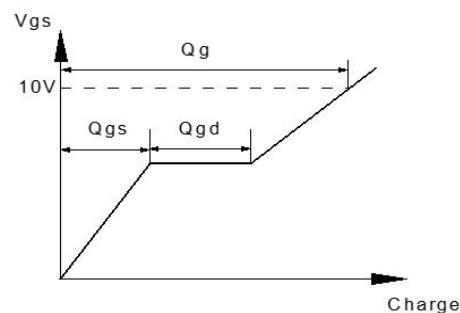
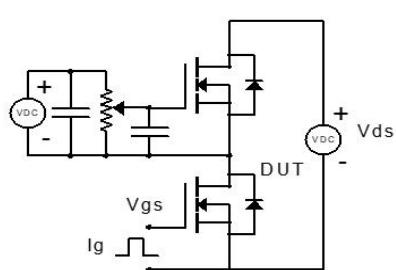


Figure 1: Gate Charge Test Circuit & Waveform

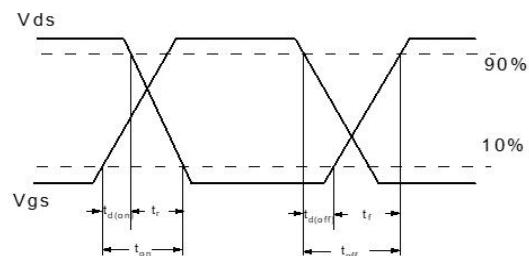
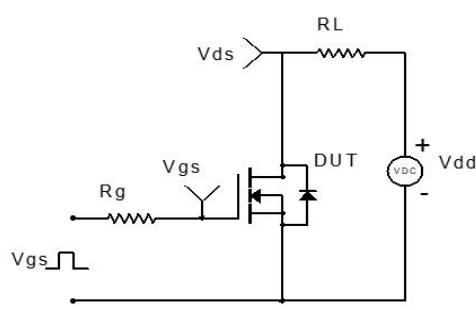


Figure 2: Resistive Switching Test Circuit & Waveform

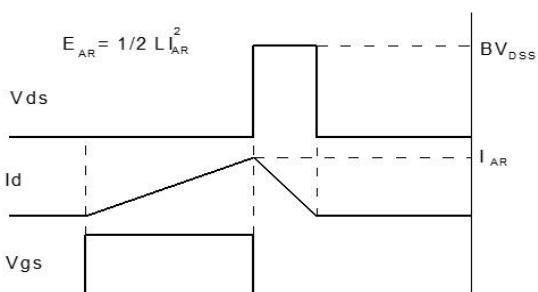
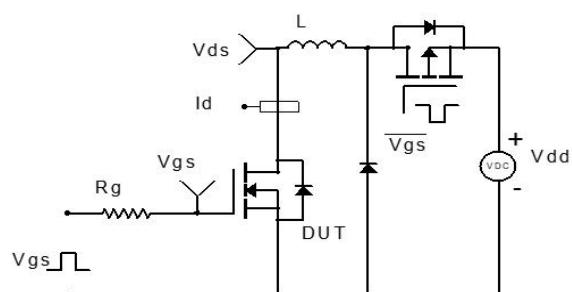


Figure 3: Unclamped Inductive Switching Test Circuit & Waveform

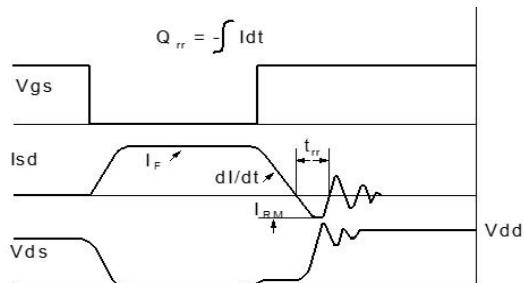
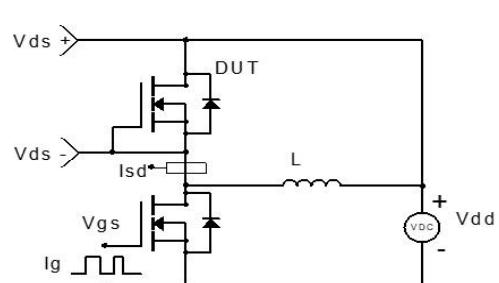
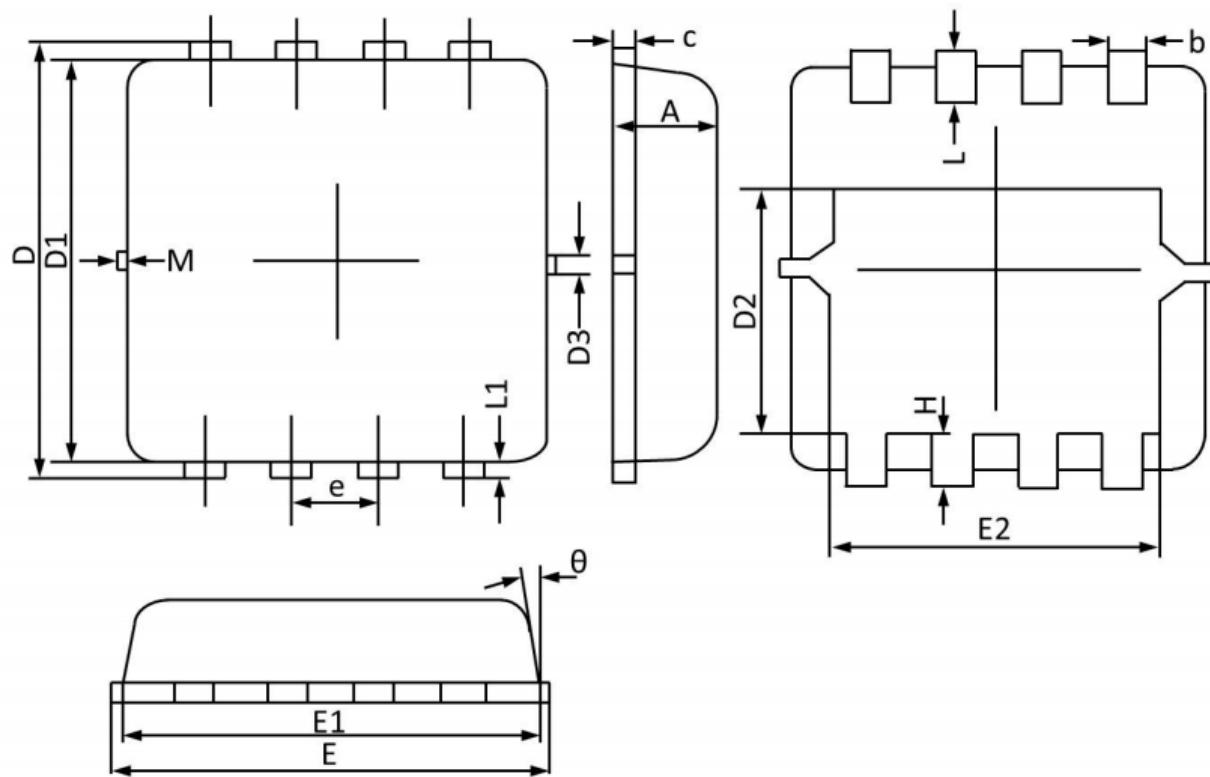


Figure 4: Diode Recovery Test Circuit & Waveform

PDFN3X3-8L Package Information (unit:mm)


DIMENSIONS

Symbol	Min	Typ	Max	Symbol	Min	Typ	Max
A	0.70	0.75	0.80	b	0.25	0.30	0.35
C	0.10	0.15	0.25	D	3.25	3.35	3.45
D1	3.00	3.10	3.20	D2	1.78	1.88	1.98
D3	--	0.13	--	E	3.20	3.30	3.40
E1	3.00	3.15	3.20	E2	2.39	2.49	2.59
e	0.65BSC			H	0.30	0.39	0.50
L	0.30	0.40	0.50	L1	--	0.13	--
θ	--	10°	12°	M	*	*	0.15